302

Accession number:20123015268693

Title: Acoustic and breathing phonon modes in bilayer graphene with Moiré patterns Authors: Jiang, Jin-Wu (1); Wang, Bing-Shen (2); Rabczuk, Timon (1)

Author affiliation:(1) Institute of Structural Mechanics, Bauhaus-University Weimar, Marienstr. 15, D-99423 Weimar, Germany; (2) State Key Laboratory of Semiconductor Superlattice and Microstructure, Institute of Semiconductor, Chinese Academy of Sciences, Beijing 100083, China Corresponding author:Jiang, J.-W.(jwjiang5918@hotmail.com)

Source title: Applied Physics Letters

Abbreviated source title: Appl Phys Lett

Volume:101

Issue:2

Issue date:July 9, 2012

Publication year:2012

Article number:023113

Language:English

ISSN:00036951

CODEN:APPLAB

Document type:Journal article (JA)

Publisher:American Institute of Physics, 2 Huntington Quadrangle, Suite N101, Melville, NY 11747-4502, United States

Abstract:The lattice dynamics properties are investigated for twisting bilayer graphene. There are big jumps for the inter-layer potential at twisting angle θ 0 ° and 60°, implying the stability of Bernal-stacking and the instability of AA-stacking structures, while a long platform in [8,55]° indicates the ease of twisting bilayer graphene in this wide angle range. Significant frequency shifts are observed for the z breathing mode around θ 0 ° and 60°, while the frequency is a constant in a wide range [8,55]°. Using the z breathing mode, a mechanical nanoresonator is proposed to operate on a robust resonant frequency in terahertz range. © 2012 American Institute of Physics.

Number of references:26

Main heading:Graphene

Controlled terms: Crystal lattices - Natural frequencies - Solids

Uncontrolled terms:Bi-layer - Breathing modes - Frequency shift - Phonon mode - Terahertz range - Twisting angle - Wide angle

Classification code:711.1 Electromagnetic Waves in Different Media - 761 Nanotechnology - 804 Chemical Products Generally - 933 Solid State Physics - 933.1.1 Crystal Lattice

DOI:10.1063/1.4735246

Database:Compendex

Compilation and indexing terms, Copyright 2012 Elsevier Inc.